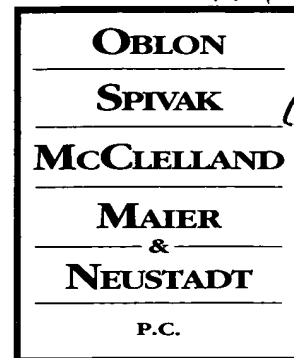




COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

"RESPONSE UNDER 37 CFR 1.116-
EXPEDITED PROCEDURE EXAMINING
GROUP 2814"

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RE: Application Serial No.: 10/622,703
Applicants: Jun MIYOKAWA, et al.
Filing Date: July 21, 2003
For: SEMICONDUCTOR LASER DIODE MODULE
Group Art Unit: 2814
Examiner: LOUIE, W.

SIR:

Attached hereto for filing are the following papers:

**REQUEST FOR RECONSIDERATION (After Final)
TERMINAL DISCLAIMER**

Our credit card payment form in the amount of **\$130.00** is attached covering any required fees. In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R. 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.


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**"RESPONSE UNDER 37 CFR 1.116-
EXPEDITED PROCEDURE EXAMINING
GROUP 2814"**

DOCKET NO: 240683US8 CONT

IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF:

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Jun MIYOKAWA, et al.

: EXAMINER: LOUIE, W.

SERIAL NO: 10/622,703

:

FILED: July 21, 2003

: GROUP ART UNIT: 2814

FOR: SEMICONDUCTOR LASER
DIODE MODULE

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REQUEST FOR RECONSIDERATION

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated June 28, 2005, please amend the above-identified application as follows:

Remarks/Arguments begin on page 2 of this paper.